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		IEEE TRANSACTIONS SLOTLINE IMPEDANCE	ON MICROV	WAVE THI	EORY AND TECHNIC	₹UES, VOL.	39, NO. 4, API	RIL 1991,	
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	+	IEEE TRANSACTIONS	SON MICROV	VAVE THE	ORY AND TECHNIQ	UES, VOL.	17, NO. 11, NC	OVEMBER 1999	
0	IEEE TRANSACTIONSON MICROWAVE THEORY AND TECHNIQUES, VOL. 47, NO. 11, NOVEMBER HIGH-IMPEDANCE ELECTROMAGNETIC SURFACES WITH A FORBIDDEN FREQUENCY BAND by Dan Sievenpiper, Member, IEEE, Lijun Zhang, Romulo F. Jimenez Broas, Nicholas G. Alexopolous, Fellow, IEEE, and Eli Yablonovitch, Fellow, IEEE							AND by ow, IEEE,	
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